

001
600 CRITICAL ITEMS LIST

08/11/80 SUPERSEDES 01/02/78

ANALYST:

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NAME P/N QTY	CRIB	FAILURE MODE & CAUSES	FAILURE EFFECT	RATIONALE FOR ACCEPTANCE
PRESSURE TRANSDUCER, 2/100 SIN 215 D0778479-6 11	215/MQZ Orifice high. CMSS: failure of internal electrical wiring or strain gauges due to an open or short circuit.	IMO ITEM: Continued indication of high ROP pressure. SIG INTERFACE: loss of accurate ROP pressure reading. OHS will calculate too much time remaining for breathable O2. MISSION: None. False indication that a surplus of ROP oxygen exists. CRM/VEHICLE: None for single failure. Possible loss of crewman with loss of OHP.	S. Design - Shorting of the 215 wiring and strain gauge is prevented through the following design features. The transition between the gauges and the sensor header is accomplished through the use of an intermediate interconnect ring. The gauges are connected to the thick film ring pads through .001 inch diameter gold wire that is bonded at each end. The sensor header pins then pick up the ring pads when the header is assembled in place. The sensor header module connection is achieved through short lengths of soft copper coated 432 gauge wire. The structural connector/electronics interface is achieved through 234 gauge tinned insulated wire. All inter connecting wires are kept as short as possible but with sufficient stress relief to prevent breakage. During assembly, all wiring can be visibly inspected once in place to insure they are not rubbing any edges. B. Test - Component Acceptance Test - The pressure transducer output is checked at the vendor (Kulite Semiconductor Inc.) per section 10.7 (Error Word Test) of Acceptance Test Procedure ATP 336. This test consists of checking the transducer output at increments from 0 psig to 7600 psig and back to 0 psig at temperatures of 70 degrees F, 0 degrees F, and 300 degrees F. Component Functional Calibration Test part A1-E-215 - The item is pressurized with a known pressure over the range of 0-7600 psig and 7600-0 psig. The output of the transducer when compared to the known pressure must be within 25% psig, except at 0 psig it shall be within 18% psig. An incorrect signal would be detected at this test. SFC PDA Testing per 215-68-007 - The item is checked for proper operation by pressurizing the end item (SOP) to a known pressure of 7200-7650 psig. The ROP is then allowed to bleed at the rate of 5.75 - 3.46 lbf/in ² /sec. The item pressure when compared to the known pressure shall be within 25% psig, except at 0 psig it shall be within 18% psig. Certification Test - The item completed the 15 year structural vibration and shock certification requirement during 10/83. Engineering changes 42805-141 (Preclude the possibility of a cable entry failure), 42806-301 (Eliminate a potential interference between transducer and ROP),	

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ANALYSIS

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NAME P/N REF	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	REQUIRE FOR ACCEPTANCE
	2/100	2137MB2A1		

42006-47P (Added gold inspection requirements and a more stringent leakage test) and 42006-490 (Added a voltage conditioning requirement and a more stringent screwing procedure) have been incorporated and verified since this configuration was certified.

C. Inspection -

Units are subjected to the following test during assembly. The electronic components in the transducer network are screened to MIL-817-213 and the hybrid assembly 0125-A 210 is received burn-in and temperature cycle across per Telite ATP 82341 to ensure their operation reliability and circuit integrity.

The -4 and -4 are the same except for minor wiring changes to comply with MIL-817-213, improved shield grounding to reduce EMI susceptibility, improved parts traceability, and increased electronic burn-in time. The strain is visually inspected during assembly to insure proper wire strain relief and that soldering conforms to RSG 5200.4 (3A-11).

1. Vendor Document (ATP 2341) Component Acceptance Test related electronic testing with specific sections (10.1) Burn-In Test done at ambient temperature and pressure for (48) hrs. min. (10.2) Insulation Resistance Test done at (100) VDC. (10.3) Power Consumption Test done at (13.9) VDC.
2. Vendor Document (RSP 2027) Burn-In of Hybrid Circuit Temp Increase to 257 degrees F for 100 hours at board level.
The units P/N 04770473-5 will be subjected to the following inspection tests during assembly.

1. Same as existing units.
2. Test performed on the amplifier level - Vendor Document - (RSP 2004/3) Temp Cycle per MIL-130-223 Method 1910 Condition C (RSP 2007) Burn-In per MIL-817-223 Method 1415, Condition at 125 (RSP 2009/3) Stabilization per MIL-817-223 Method 1300, Condition C.

D. Failure History -

J-Box 213-001 (S-23-63) Transducer read full scale. The full scale reading was the result of an open circuit in the transducer electronics module. The open circuit was the result of a tinned gold lead wire ball from one of the integrated circuit aluminum pads. The lifting of the gold ball connection was attributed to random contamination of

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NAME P/O NOY	EMI S/NO	FAILURE MODE & CAUSES DISINTEGR:	FANING EFFECT	RATIONALE FOR ACCEPTANCE
				<p>the joint before joining. Kulite's SF sheets were changed to add a mandatory visual inspection of chips and balls for cleanliness prior to joining field units N-201-205-0002 (10-F-01). Transducer read high during SOP P06. High reading was caused by calibration at only one temperature by Kulite. The transducer was successfully recalibrated by Kulite. Kulite's calibration procedure was revised to make calibration at all three calibration temperatures (0-70-100 °F).</p> <p>J-EMI-219-002 (4-16-85) the transducer had a high, erratic, reading. This high reading was the result of using the unit in an electromagnetic field of greater magnitude than the transducer design or test limits. The present EMI requirement is being revised to a reduced (EMI 001) requirement that exempts temporary EMI induced outages.</p> <p>G-EMI-211-002 (1-10-87) The transducer had damaged cable connector. This was the result of the use of Scotch weld which made the cable attachment too rigid. The Scotch weld will be deleted in all 4-66 configurations and subsequent related failures.</p> <p>H-EMI-151-002 (4-22-87) Shield circuit resistance too high. The high resistance was a result of the use of a substrate on the interfacing connector shell surface. This prevented proper grounding of the mating connector. EC-42007-219-2 adds a grounding ring, provided by Bendix Corp. to all units. There is no impact on certification.</p> <p>N-EMI-213-004 (4-23-87) the electrical bonding between the sensor and oxygen manifold was not as specified limits. This was the result of Torquen being applied between the mating surfaces during assembly. Assembly Operation sheets were revised to clarify areas of application.</p>

E. Ground Forward -
 tested per FEM-0-009, Transducer and DCN Gauge Calibration Check, verifies the DCN SMP pressure reading is within 477 psi of the SOP page (2134).

F. Operational Use -
 Error Response -
 EVA : Since EMI termination is required as soon as SOP is sounding and this failure is not detectable, EMI termination would continue.

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NAME P/N QTY	CRIT	FAILURE MODE & CAUSES	FAILURE EFFECT	MITIGATION FOR ACCEPTANCE
	2/100	DISCONNECT		Special training Standard training Standard EMU training covers this failure mode. Operational Considerations - CMA checklist procedures verify hardware integrity and system operational status prior to EVA. Flight rules define EMU as last way down to stowage. Real Time Data System allows ground monitoring of EMU systems.

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